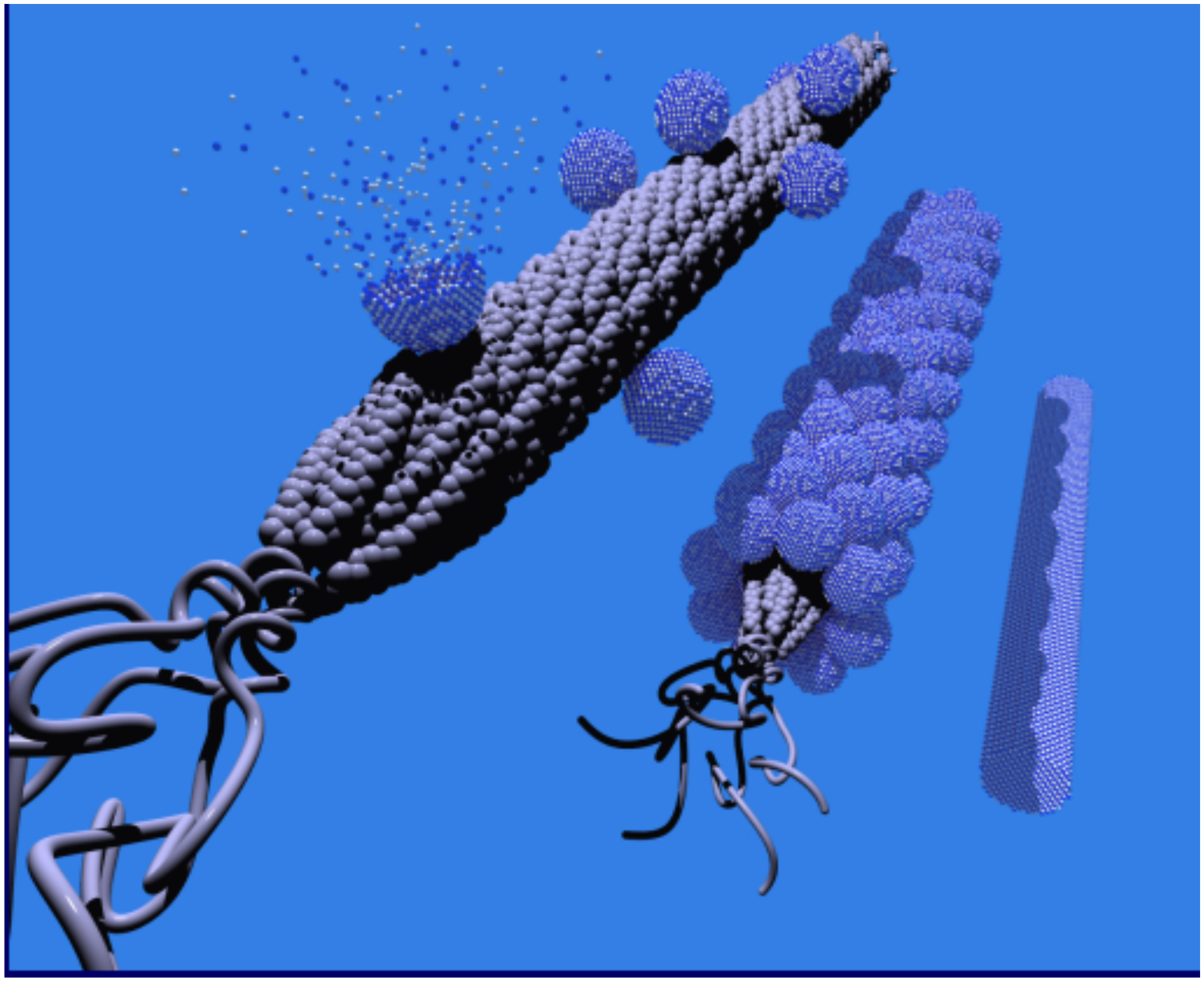
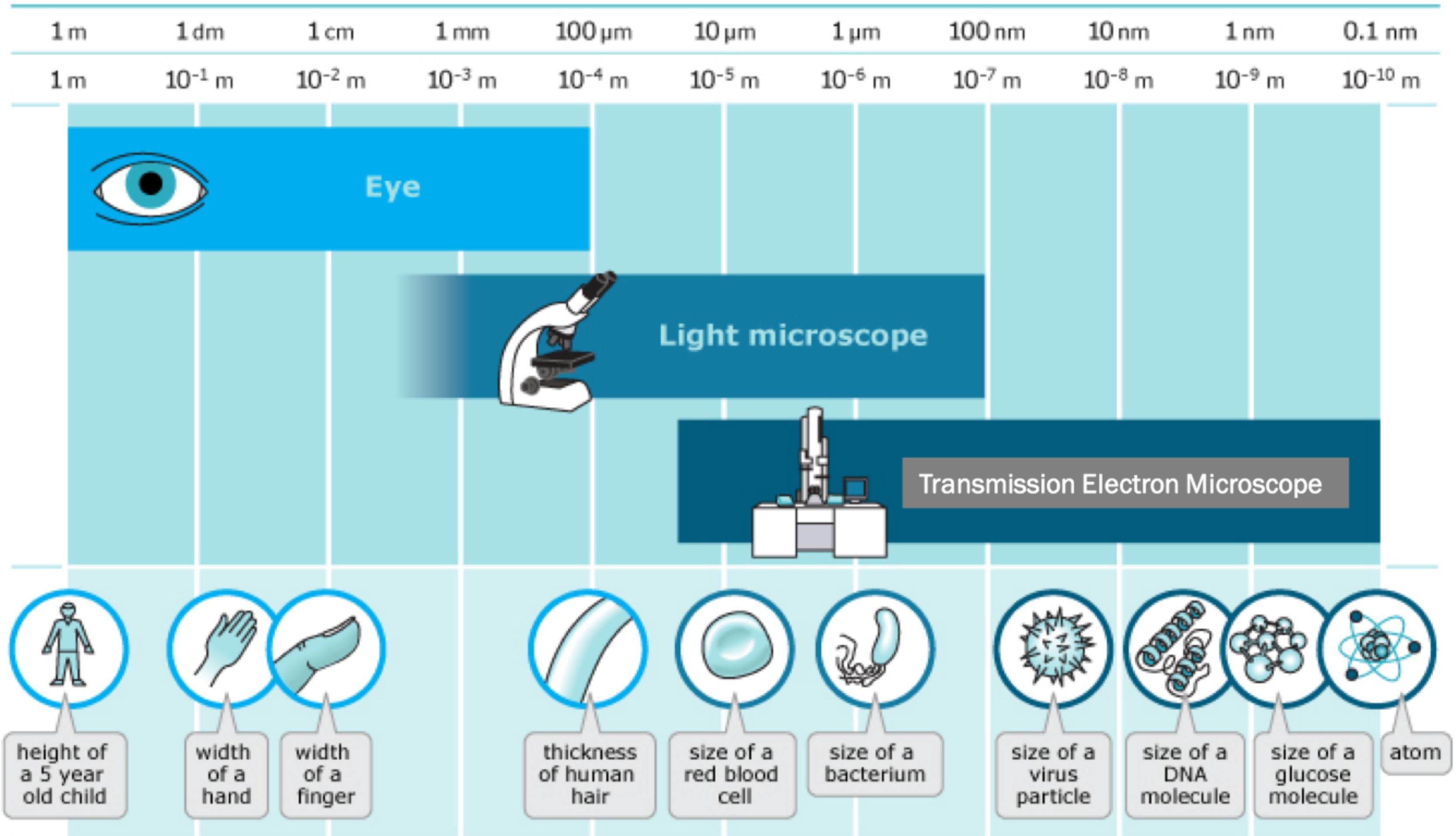
Virus Nanowires and Nanoparticles



Resolving Power of Microscopes

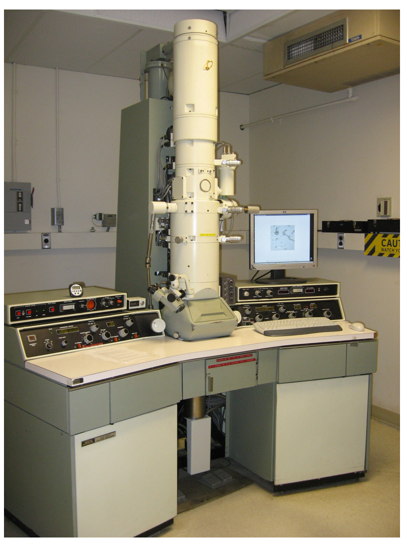


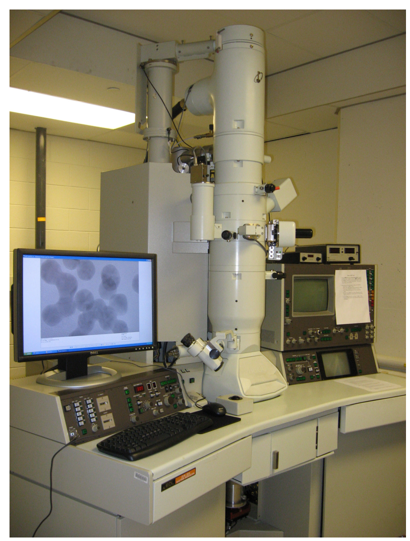
What’s TEM

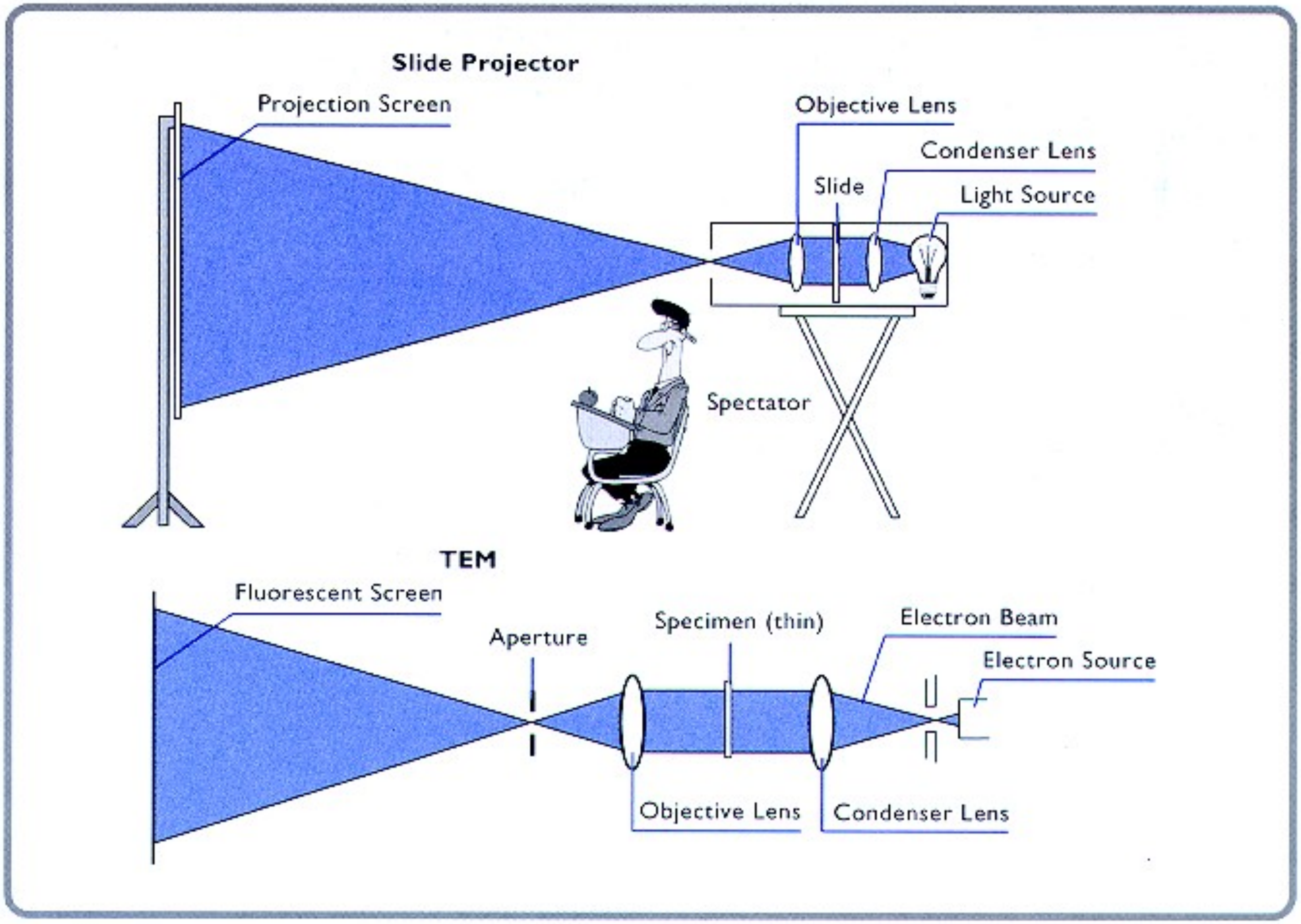
• An electron-optical microscope that uses electromagnetic lenses to focus and direct an electron beam.

• Bright field imaging is from electrons interacting with electron dense materials to cast a shadow on a screen or camera.

• High voltages between 10KV and 1MV. The higher the voltage is, the shorter the wavelength of electrons, giving the better resolution. **200KV.** ultimate point-to-point resolution of 0.19 nm



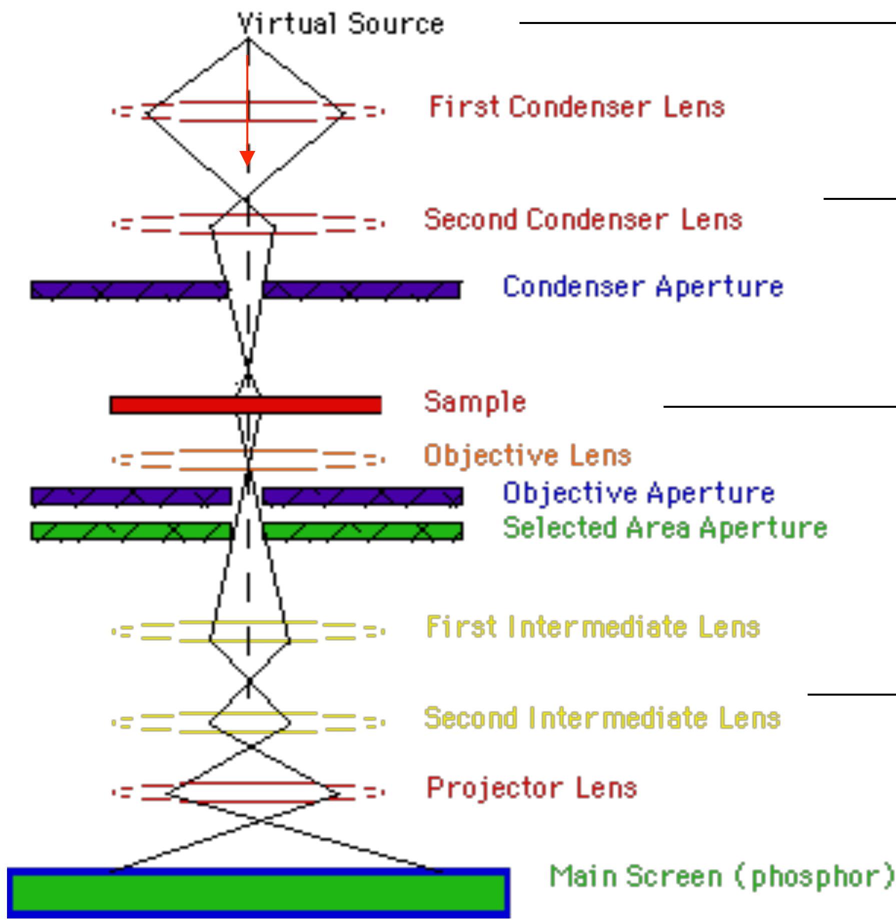


http://labs.mete.metu.edu.tr/tem/TEMtext/TEMtext.html

What’s TEM

Electron beam path



Source is a beam of high velocity electrons

Lanthanum hexaboride cathode or tungsten

Electron beam focused by condenser lens onto specimen

If a sample is thin enough, electron beam can pass through it

Transmission/scattering beam is focused by objective lens/intermediate/projection lens. Final image/electron diffraction pattern forms on a screen for viewing

Yong Zhang (CMSE TEM facility)

Why We Need TEM

The main use of the TEM is to examine the microstructure structure, composition, and properties of specimens in ways that cannot be examined using other equipment or techniques.

Morphology (Bright Field Image, Dark Field , HRTEM)

- The size, shape, morphology, and distribution of the particles as well as their relationship to each other on the scale of atomic diameters.

- Contrast comes from electrons interacting with electron dense atoms in the sample, the scattered electrons cause a shadow to be cast on the camera or screen.

- Crystalline samples scatter more electrons than noncrystalline samples, so amorphous samples have less contrast than crystalline samples

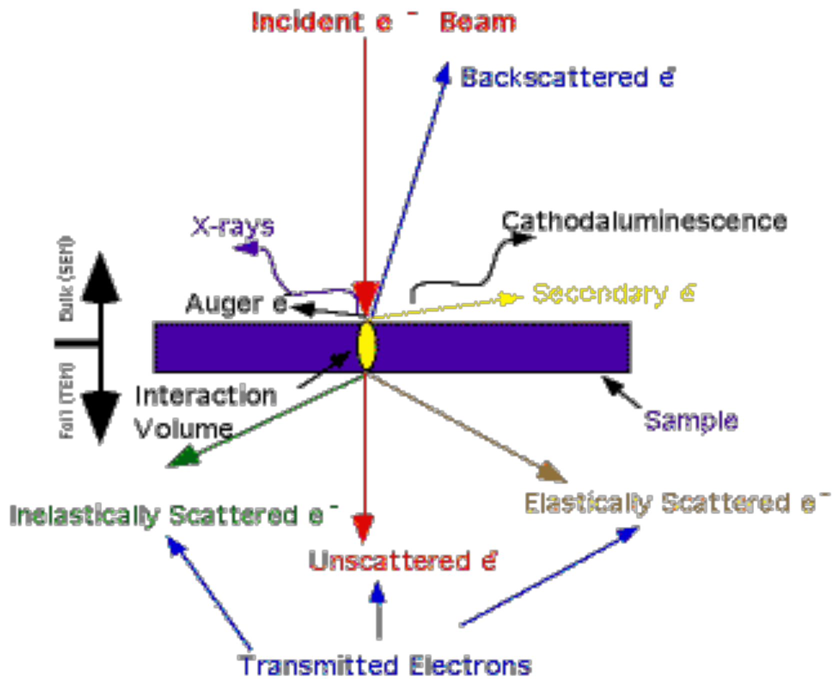
Why We Need TEM

- **Crystallographic Information (Electron Diffraction, HRTEM)**
  - For crystalline samples, crystal structure, degree of ordering, and detection of atomic-scale defects in areas a few nanometers in diameter can be determined

- **Compositional Information (Energy dispersive spectroscopy (EDX), Electron energy loss spectroscopy (EELS)**The elements and compounds the sample is composed of and their relative ratios, in areas a few nanometers in diameter

What's TEM

Different equipment in TEM is then used to collect scattered electrons produced by the specimen-electron interaction, giving different types of information

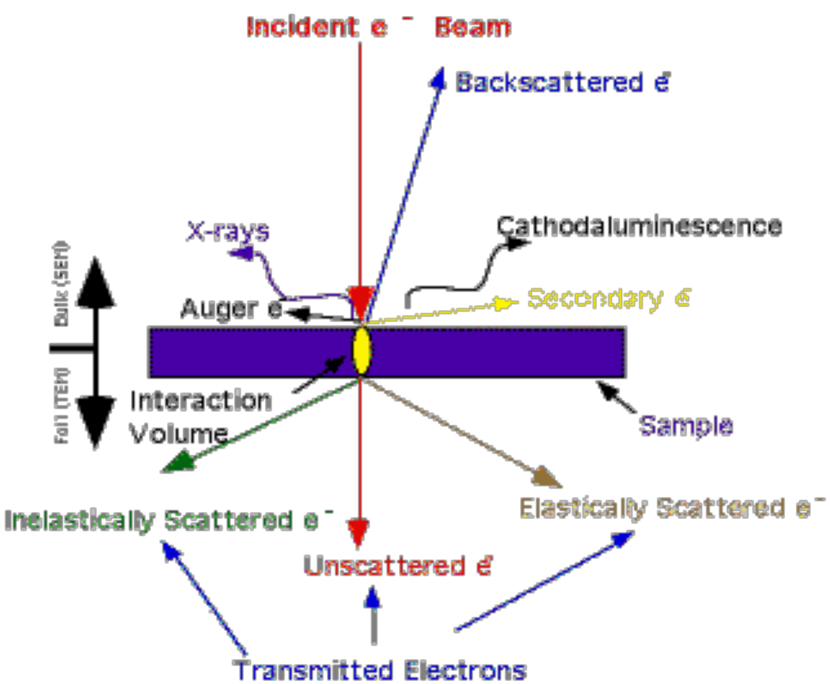


} Compositional Information

} Morphology & Crystallographic Information

Yong Zhang (CMSE TEM facility)

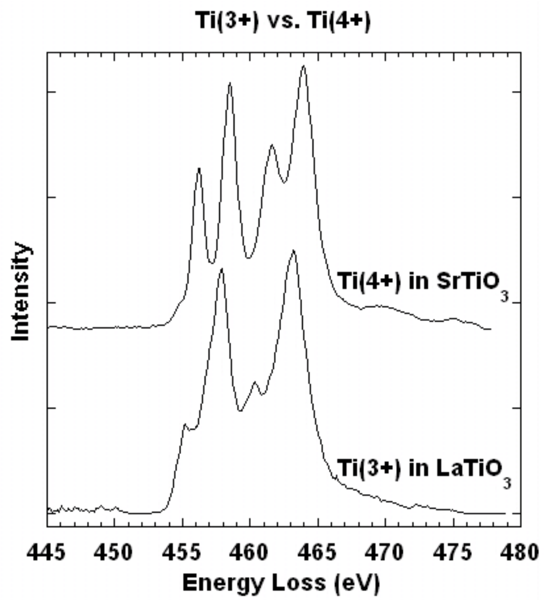
Elemental mapping and information



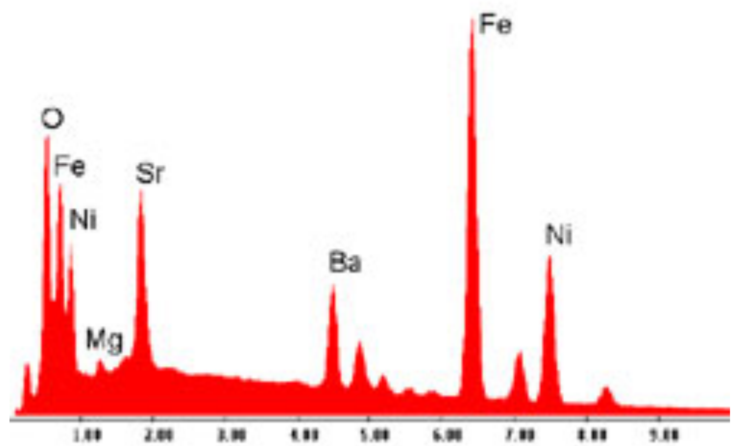
- Elemental mapping can be done by two methods, STEM and EELS
- STEM involves rastering an electron beam through a sample and determining the elemental composition of each spot by either X-ray analysis or EELS (element specific)

Elemental Analysis

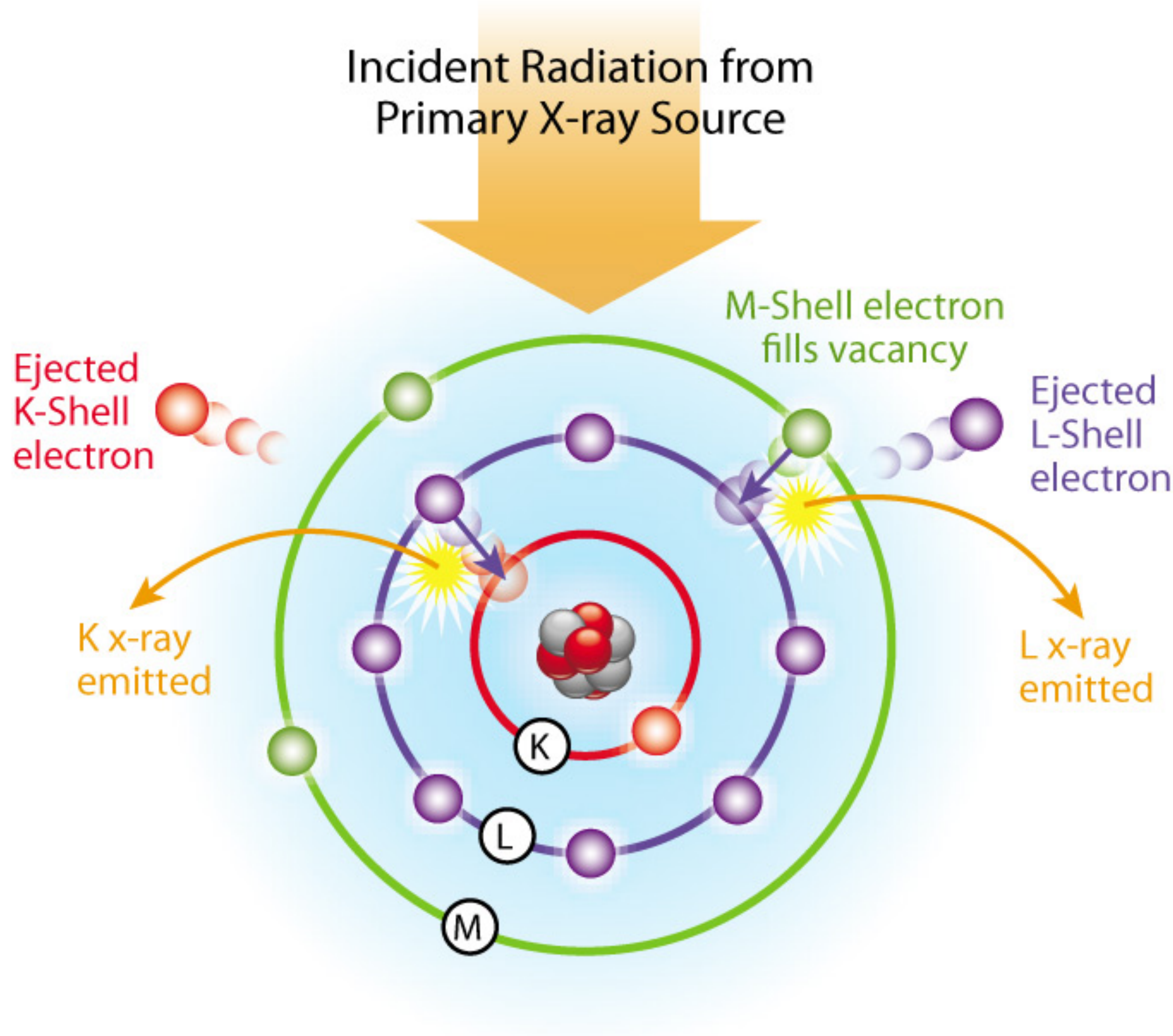
- The e^- beam has the energy to remove core electrons
- This causes for a measurable loss of energy in the electron beam (EELS)
- And also for the emission of X-rays (EDX)
- Both techniques are element specific and can be combined to show images that isolate where each element is present in the sample



EELS of Titanium particles shows a difference between Ti^{3+} and Ti^{4+}

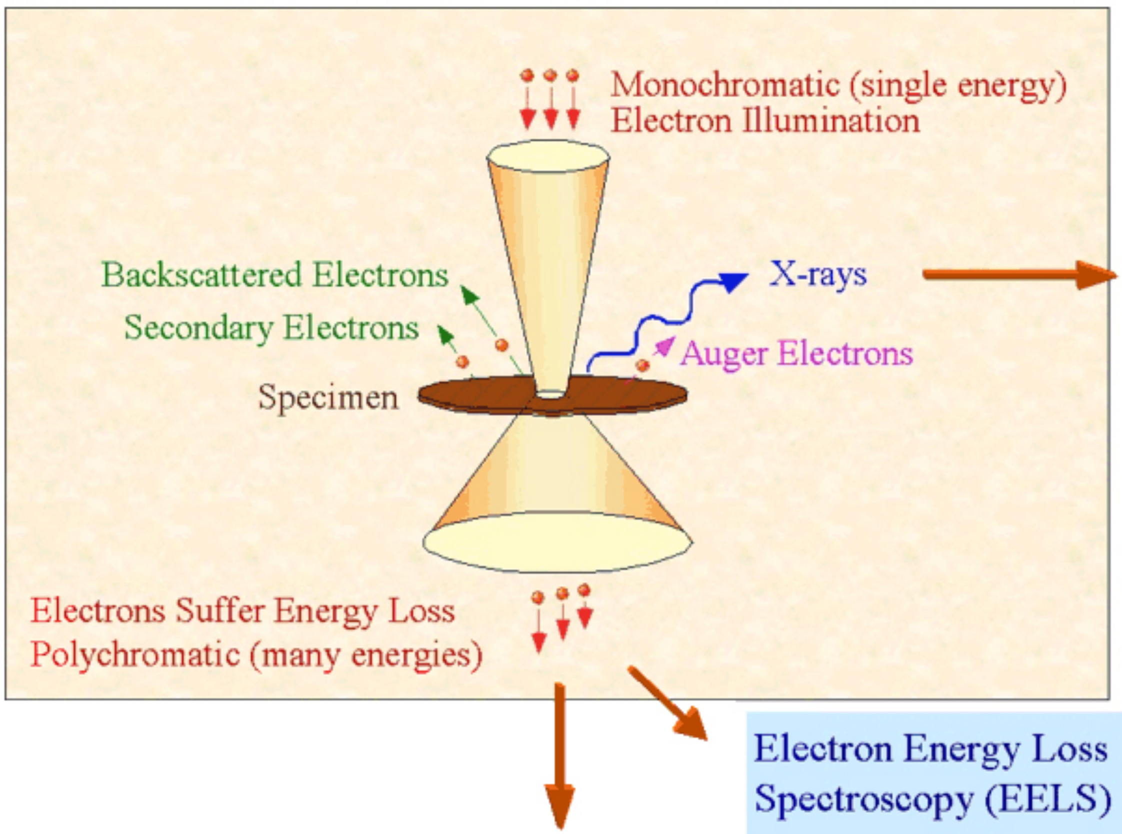


EDX of $BaSrO_x$ shows all the elements present in the sample


Incident Radiation from
Primary X-ray Source
M-Shell electron
fills vacancy
Ejected
K-Shell
electron
Ejected
L-Shell
electron
K x-ray
emitted
L x-ray
emitted
K
L
M

Energy Dispersive X-ray Spectroscopy (EDXS)

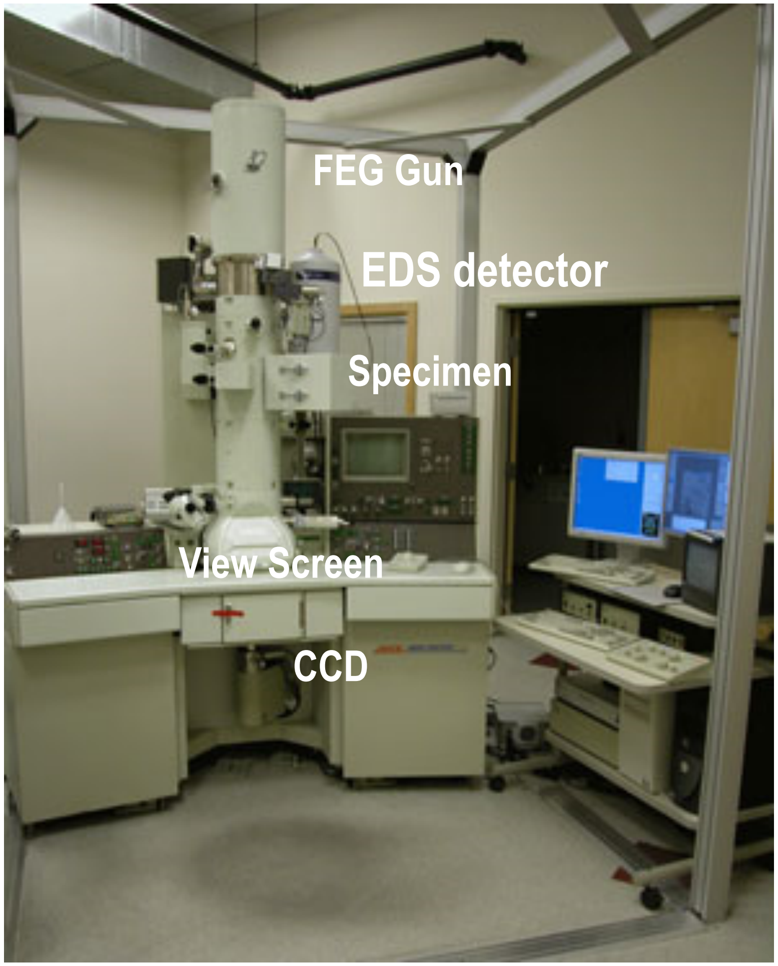
Different elements emit different characteristic X-rays when excited by an electron beam.
These X-rays can be used to identify the elements present, quantify their relative or absolute concentration, and map their distribution.



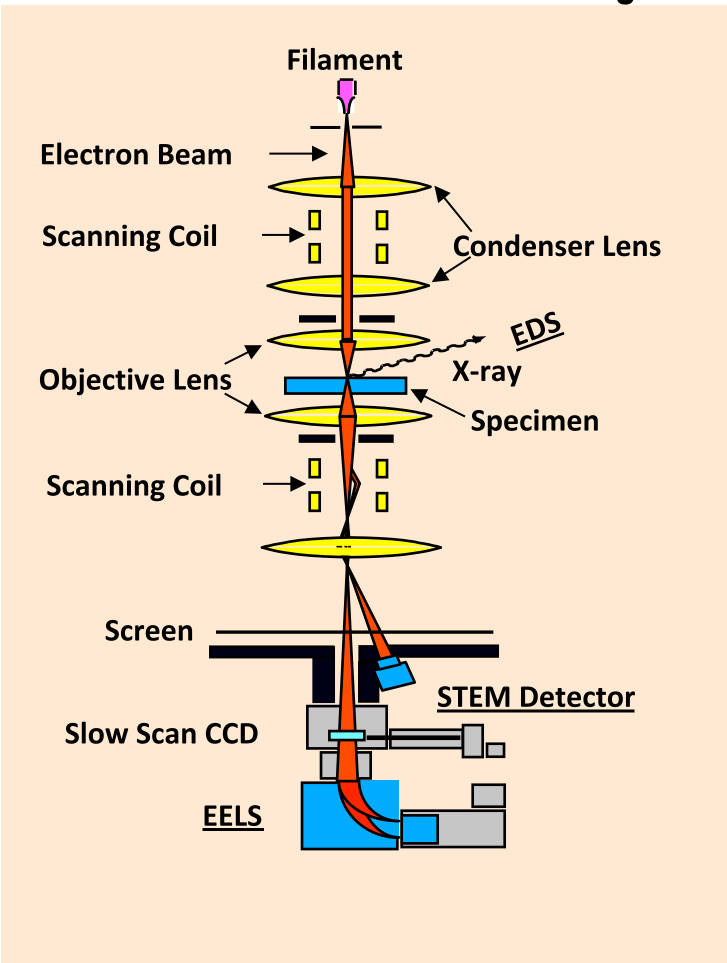
Different elements cause incident electrons to lose different amounts of energy. EELS can be used to identify the elements present, quantify their relative or absolute concentration.

JEOL 2010 Field Emission Gun(FEG) TEM

2010FEG TEM Photo



2010FEG TEM Schematic Diagram



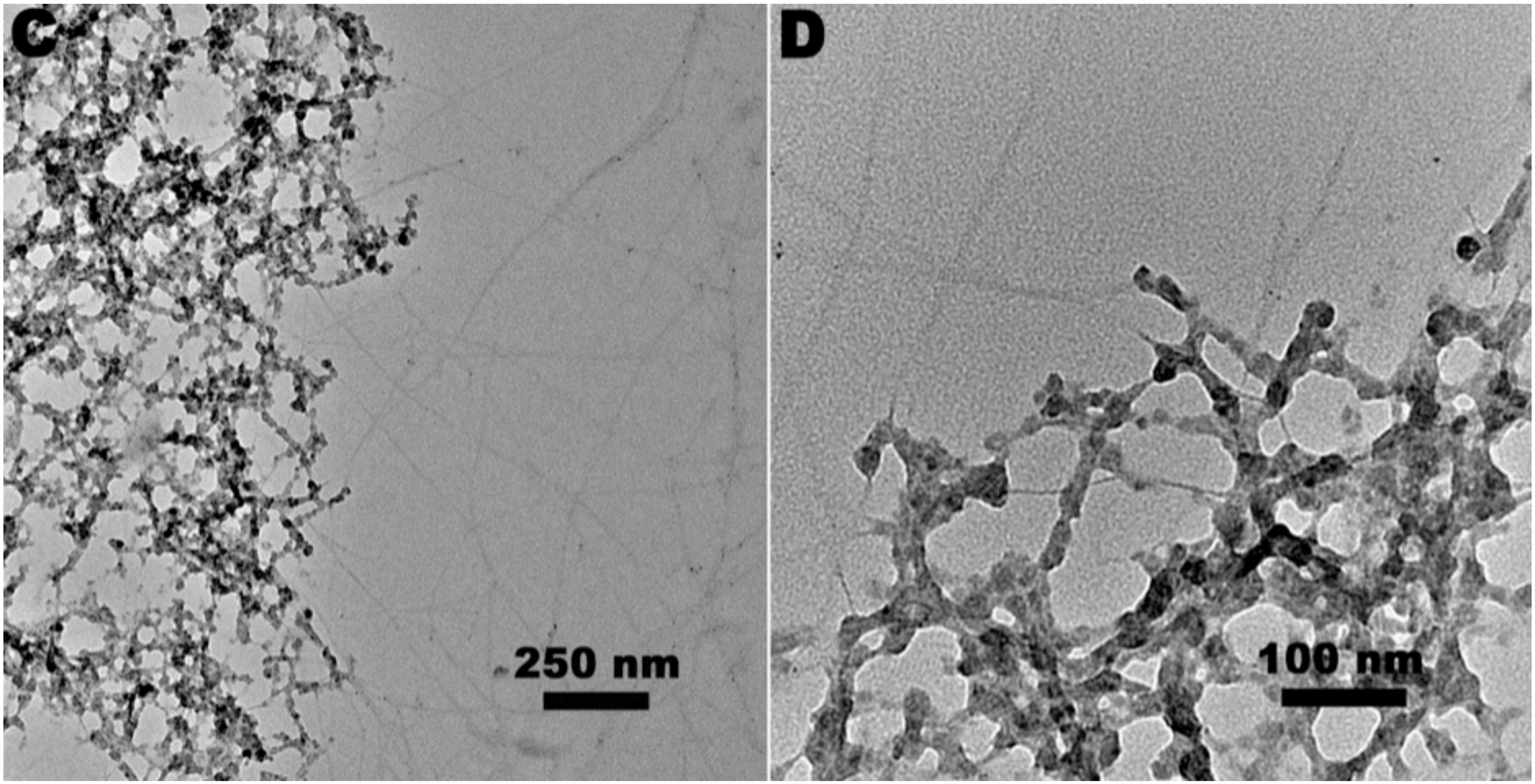
2010FEG TEM Characteristics

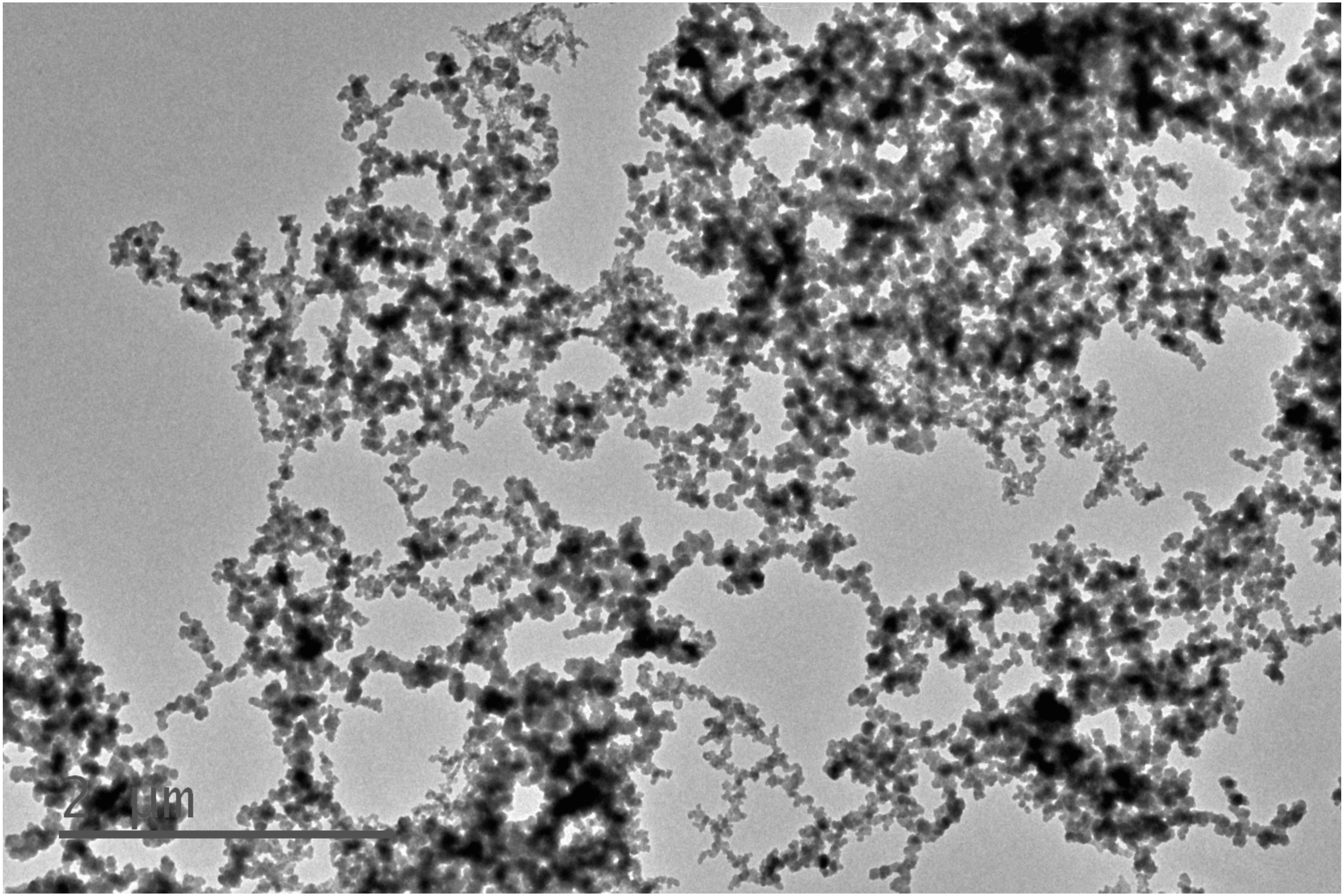
1. Point Resolution : less than 0.2nm

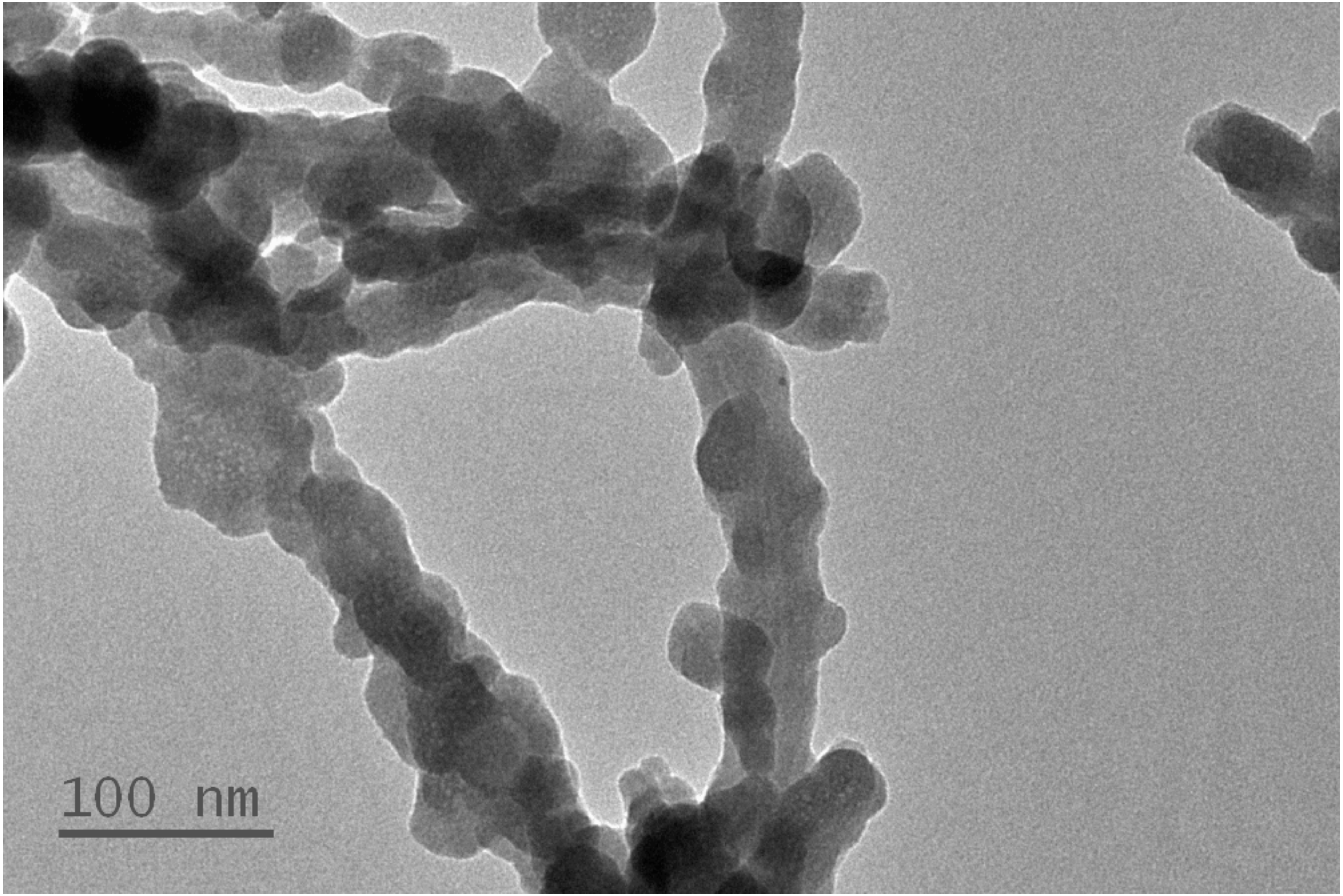
2. Brightness : 2-order higher brightness than with the LaB6 electron gun,(JEOL 2010 TEM)
3-order higher with tungsten thermionic gun(JEOL 200CX TEM)

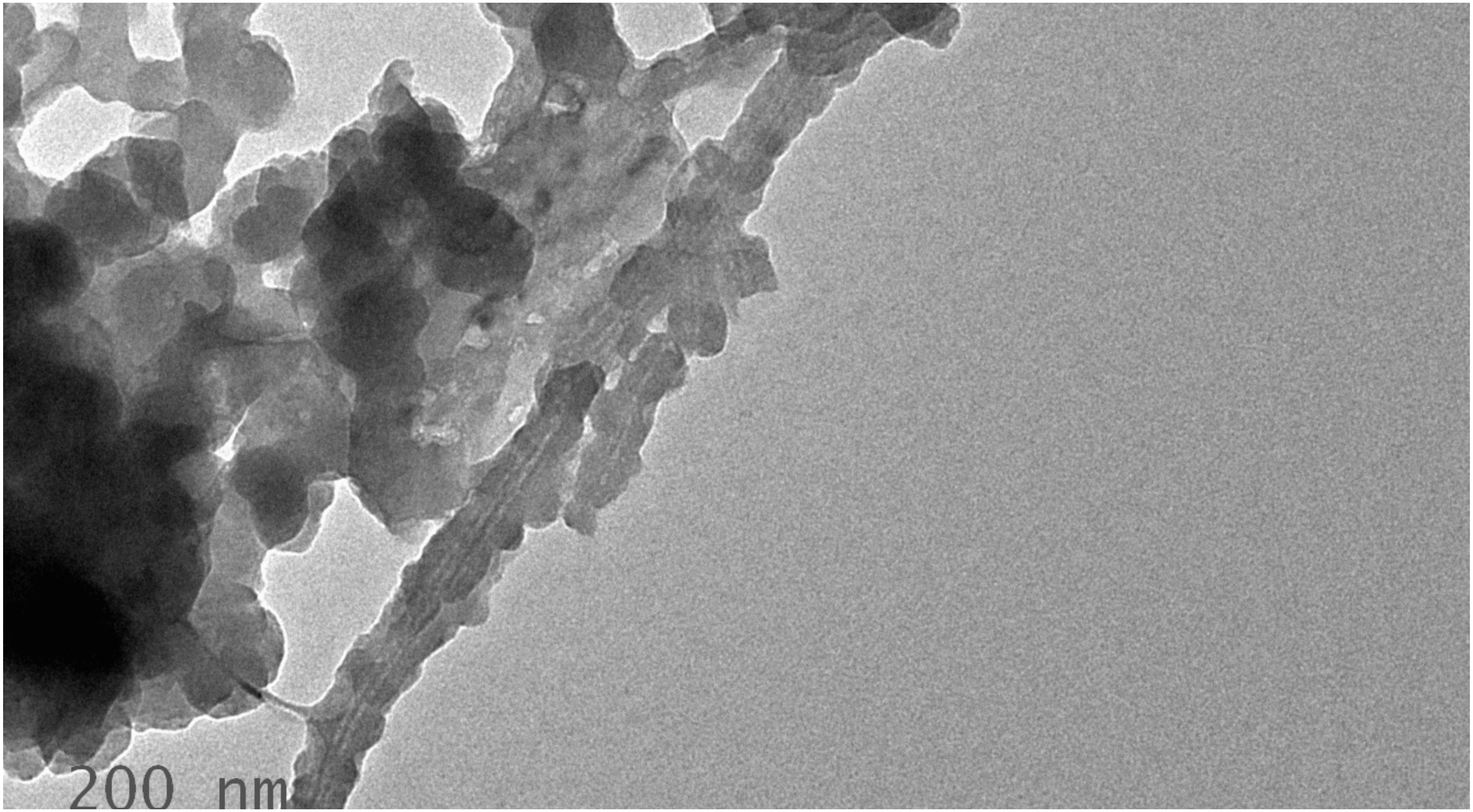
3. Nanoanalysis : Atomic arrangement, Grain Size, Crystal Orientation, Defects,
Chemical analysis - elements, composition

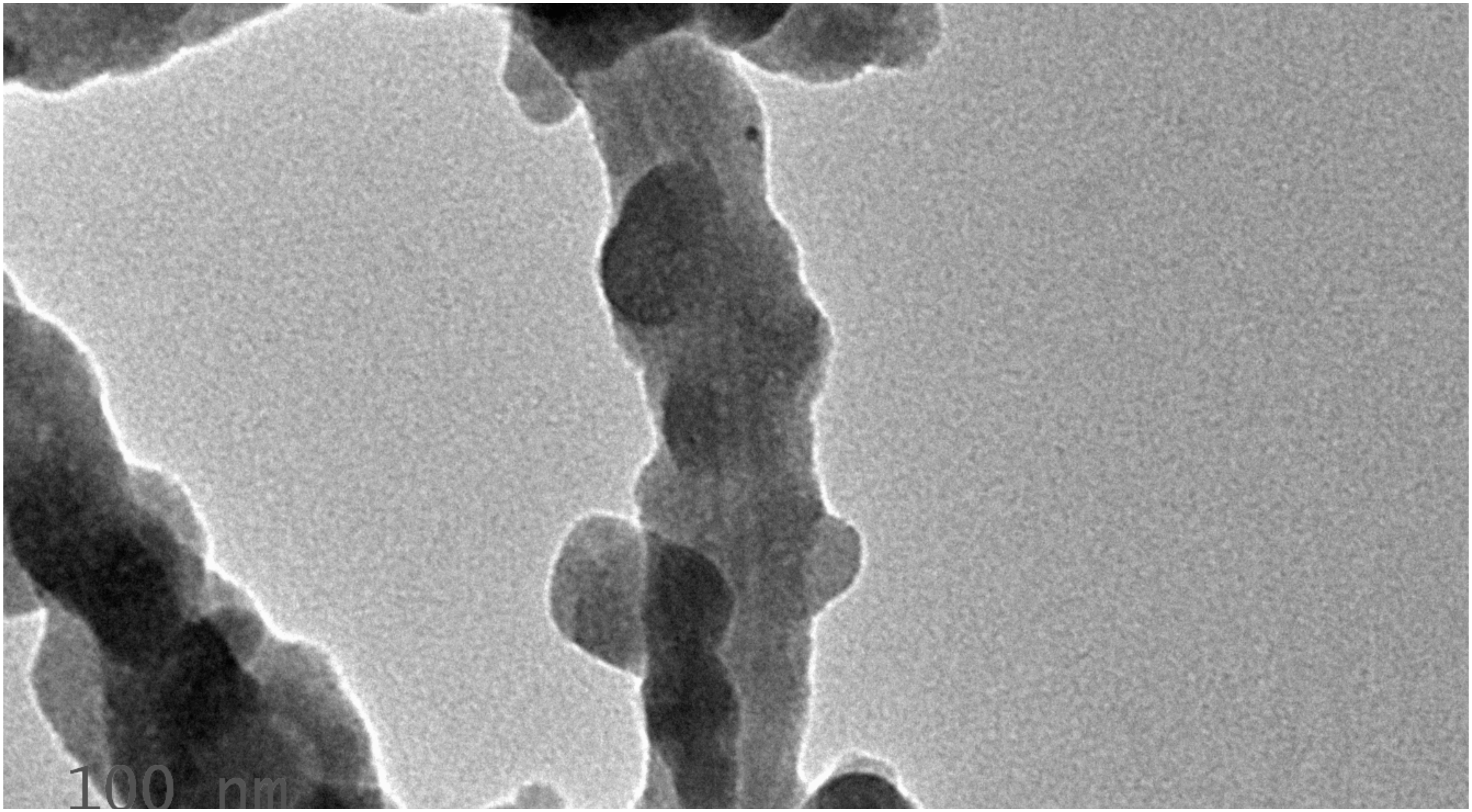
$FePO_4$ Nanowires



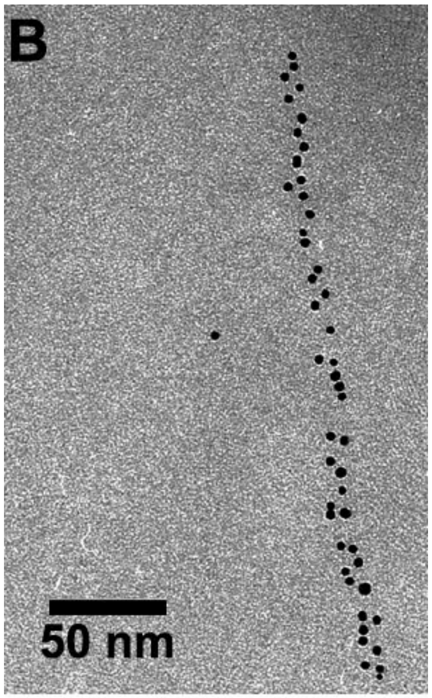

2 μm

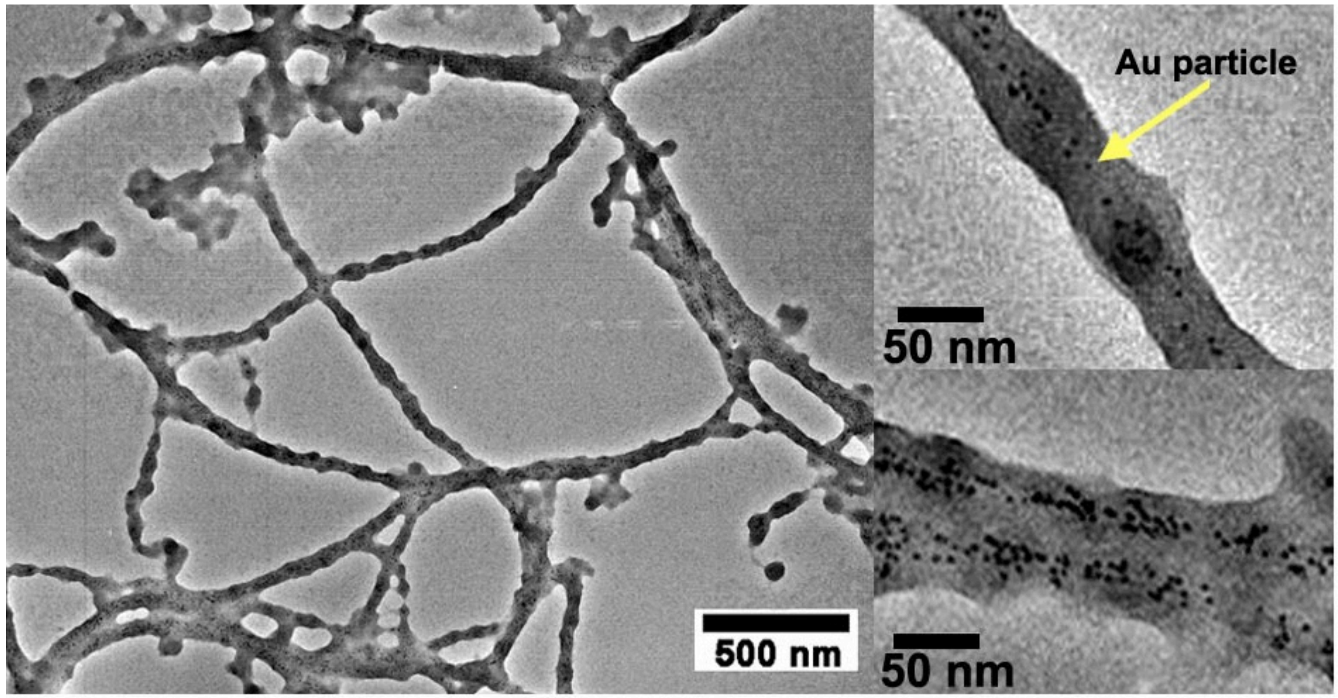

100 nm


200 nm


100 nm

Genetic Modification Produces New Hybrid Anodes for Increased Capacity Au-Co_3O_4 Nanowire

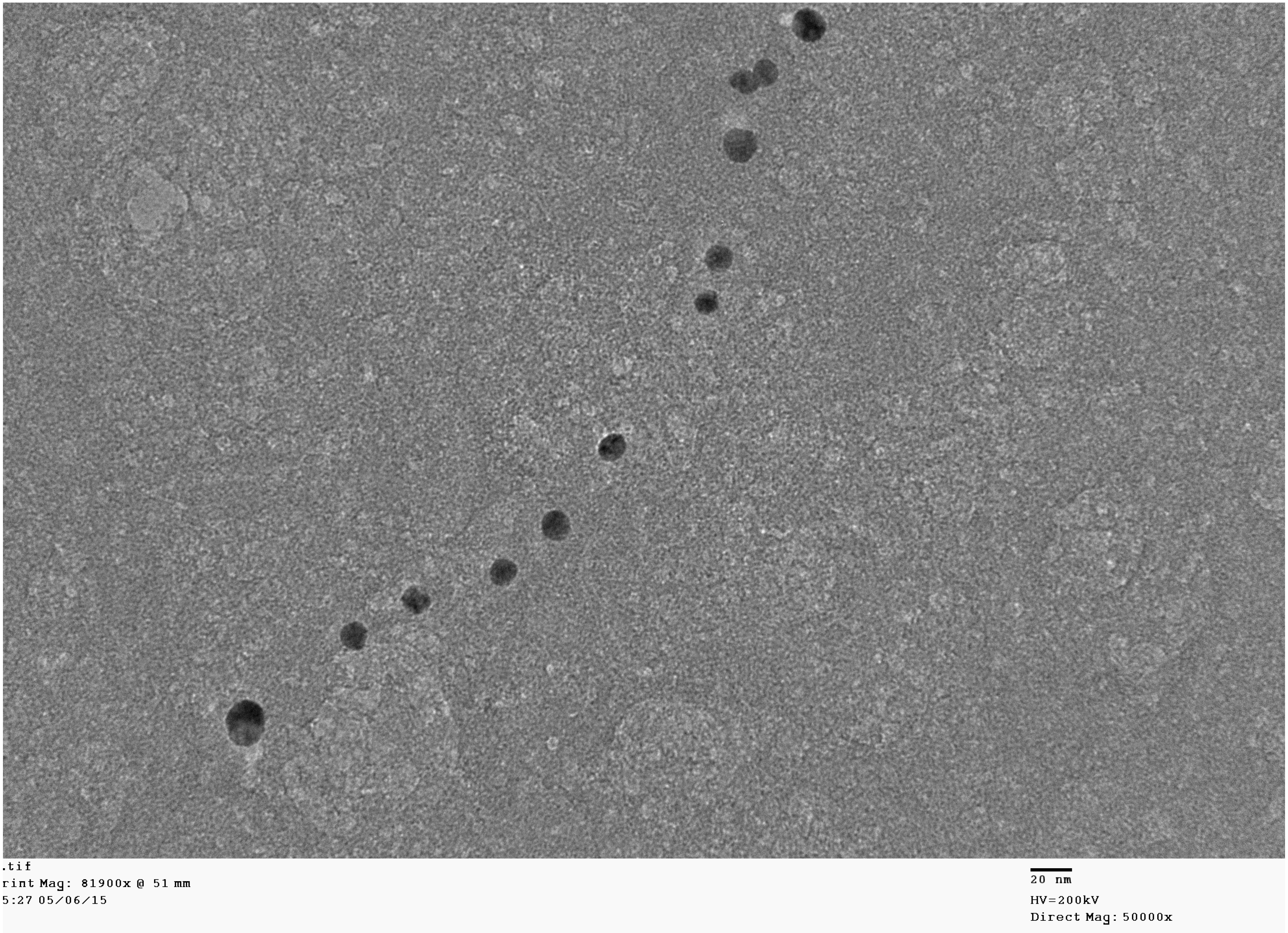




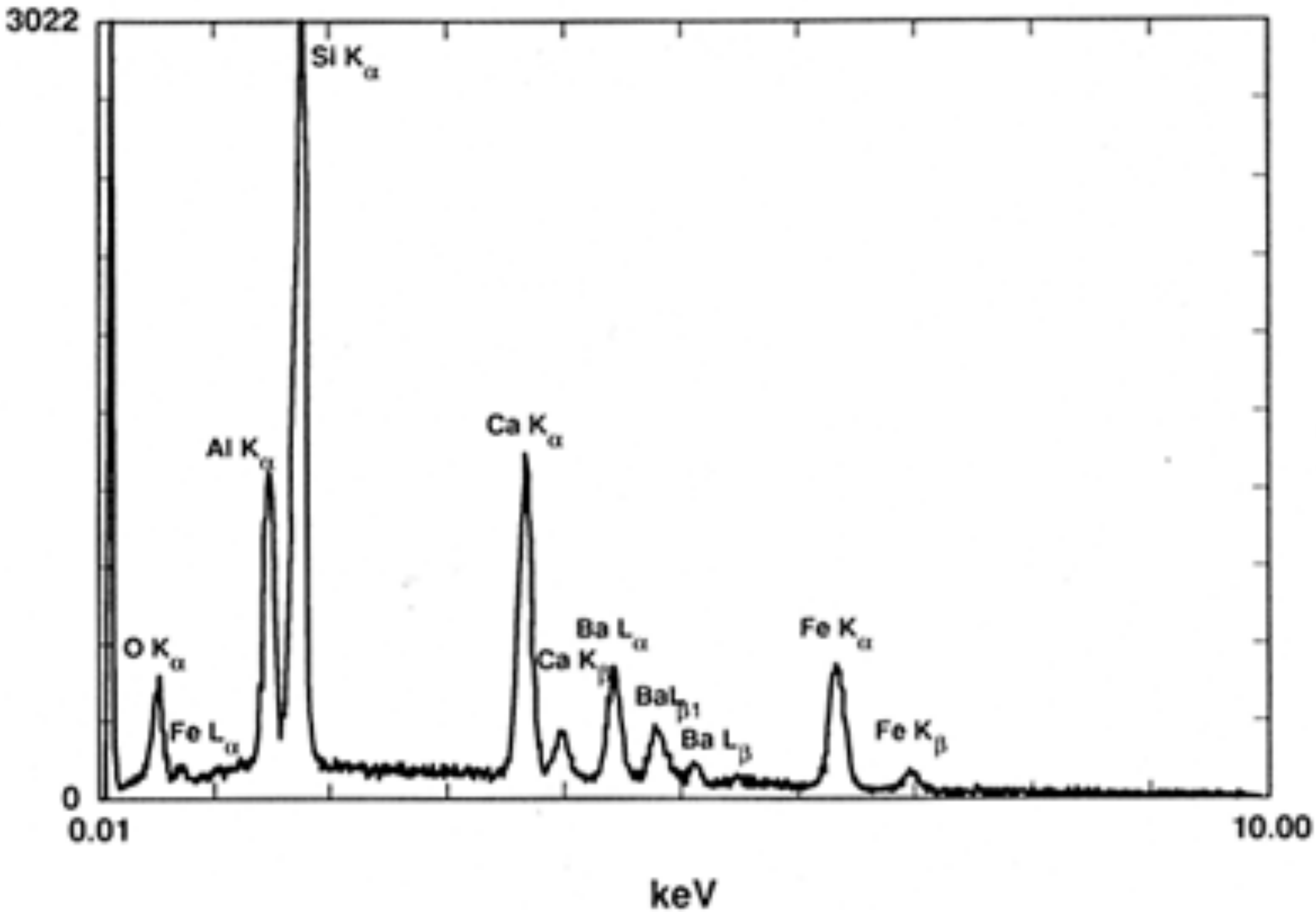
Gold nanoparticles
bound on the virus

Cobalt oxide nucleation
& growth

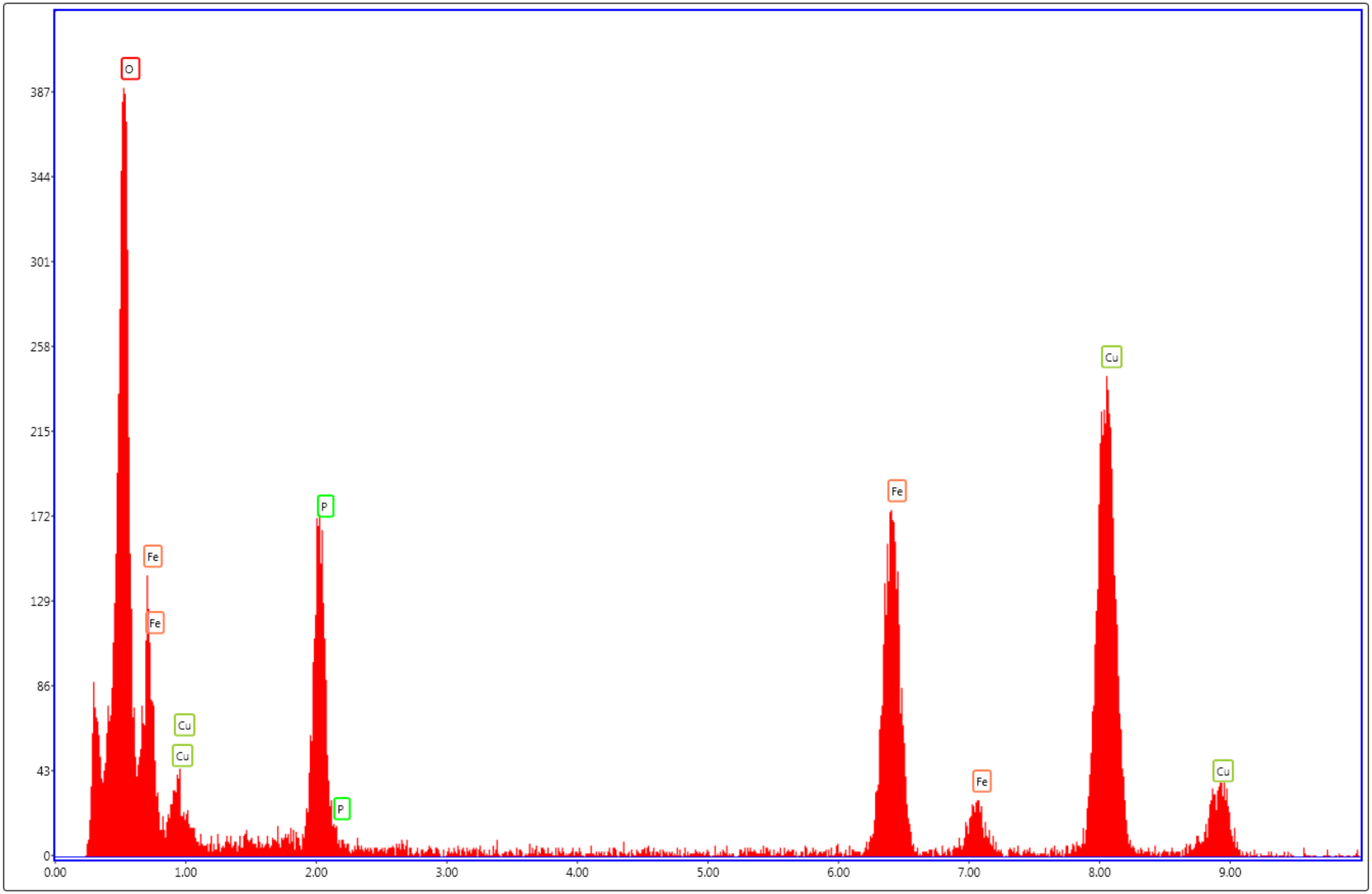
Has gene to grow co oxide and gene to bind gold



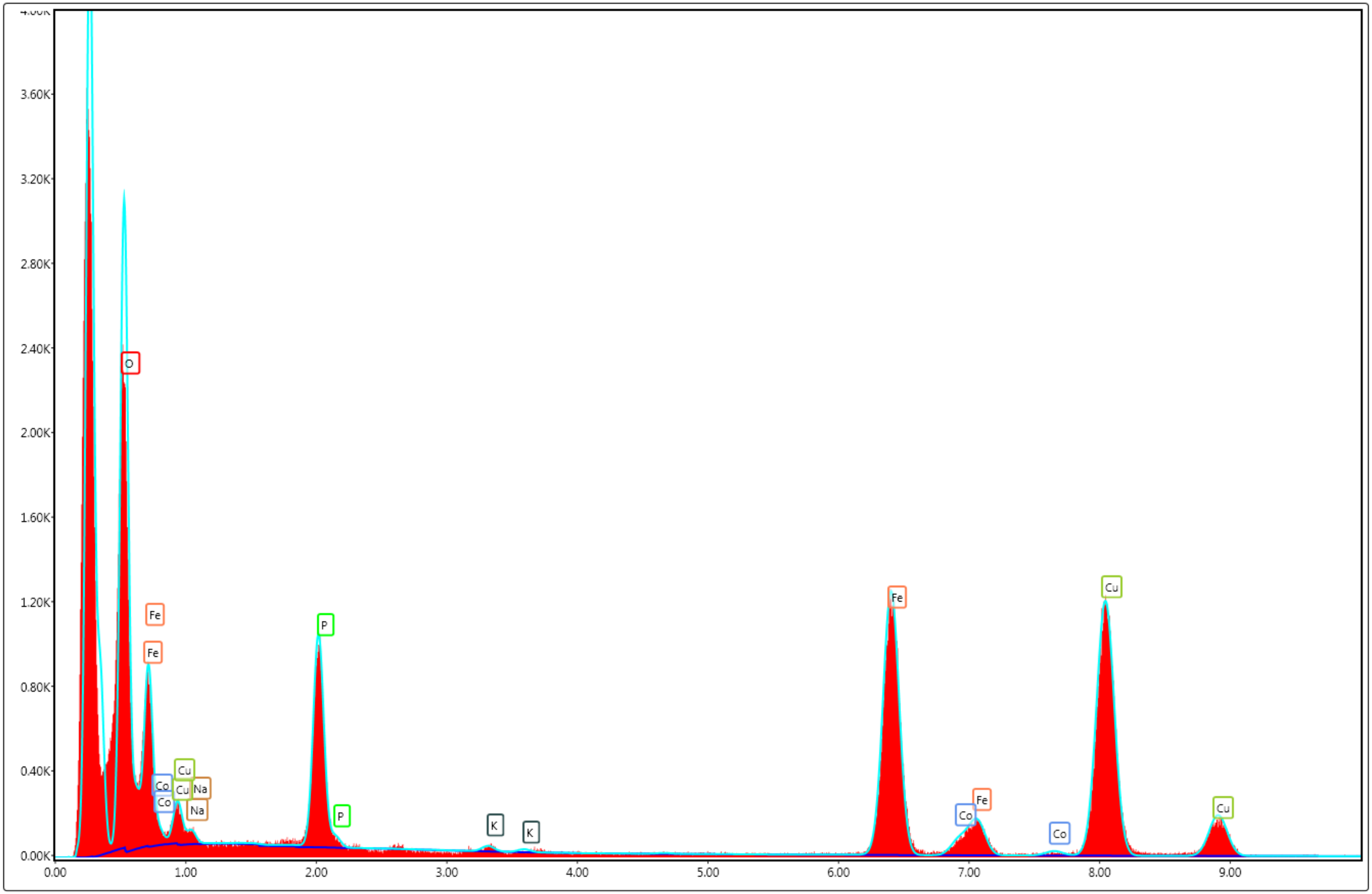
Purple MW 5nm



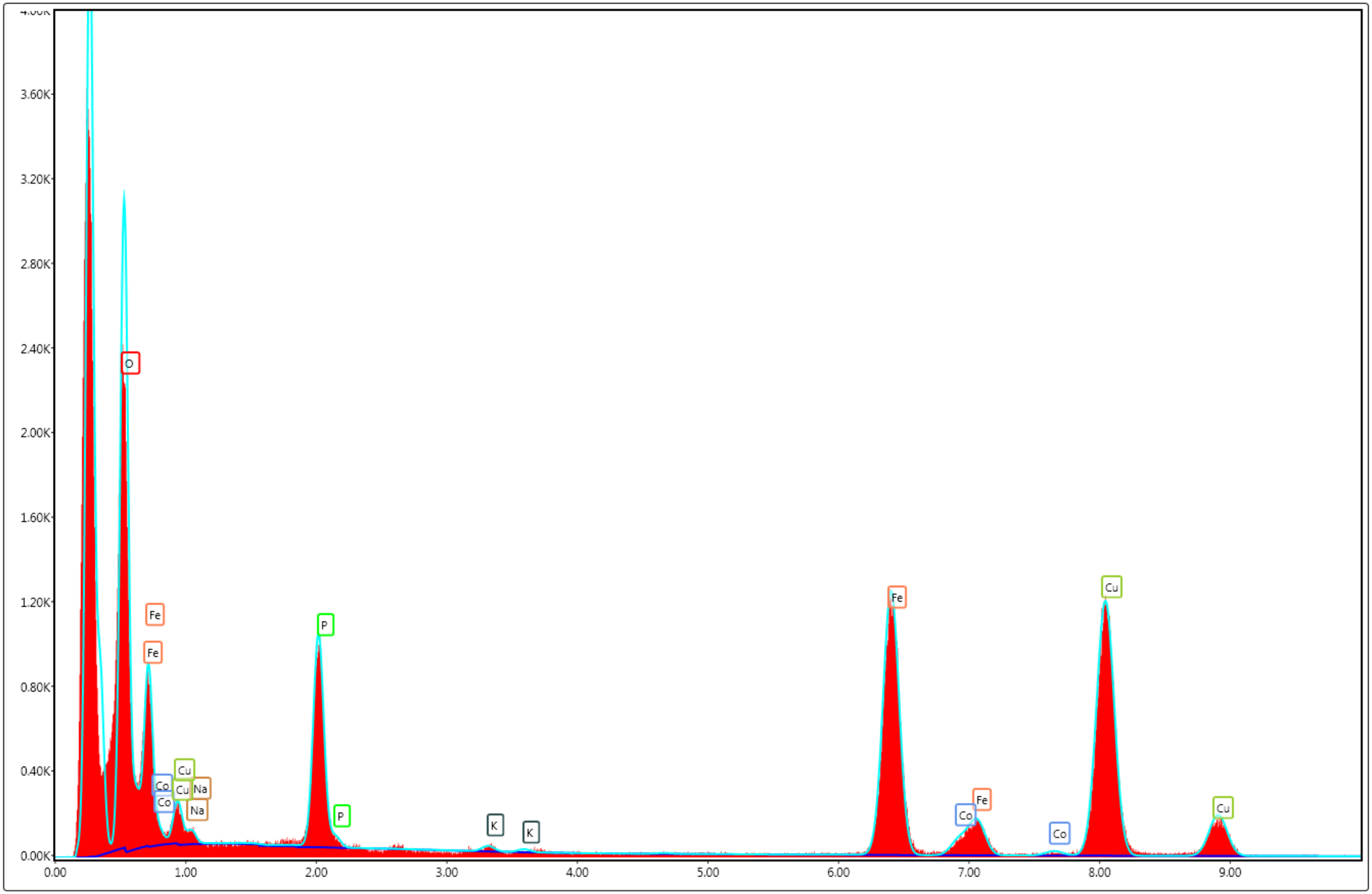
3022
0
0.01
10.00
keV
Si K_α
Al K_α
Ca K_α
O K_α
Fe L_α
Ca K_β
Ba L_α
Ba$L_{\beta1}$
Ba L_β
Fe K_α
Fe K_β



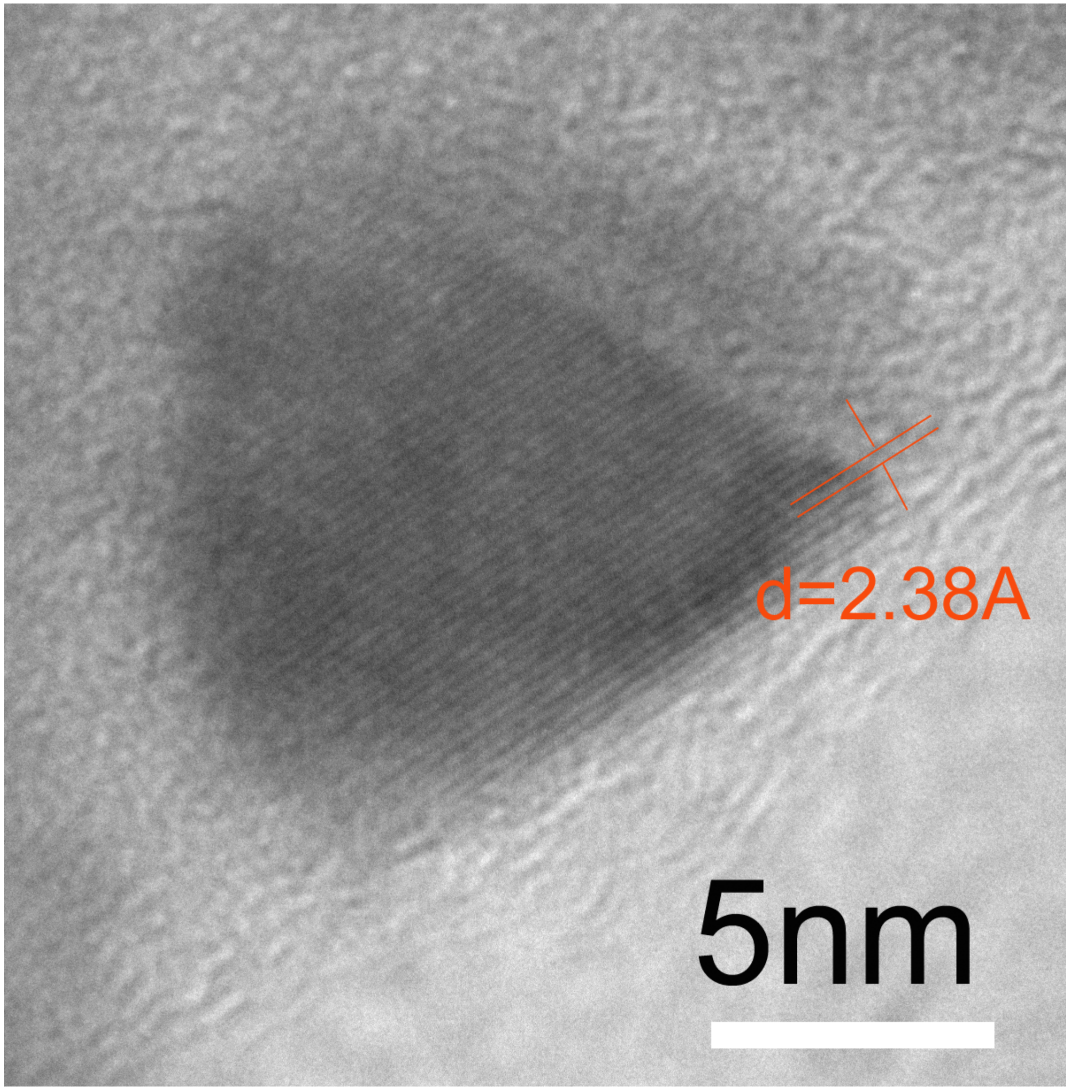
Status: Idle CPS: 4026 DT: 1.4 Lsec: 10.0 0 Cnts 0.000 keV Det: Apollo XLT2 Windowless

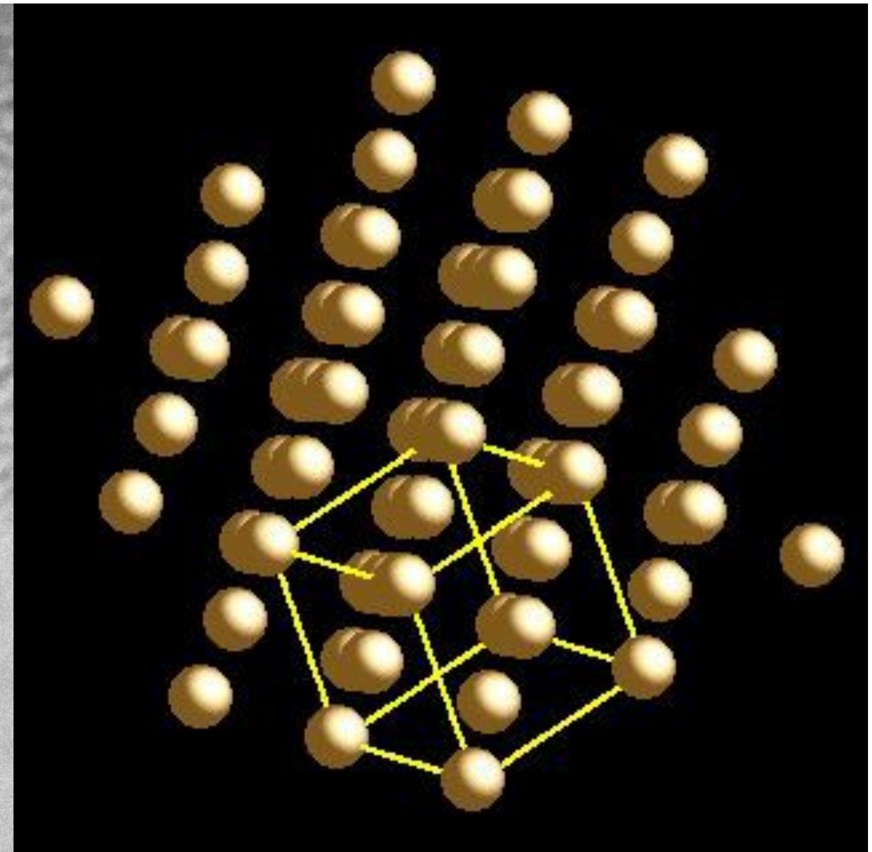


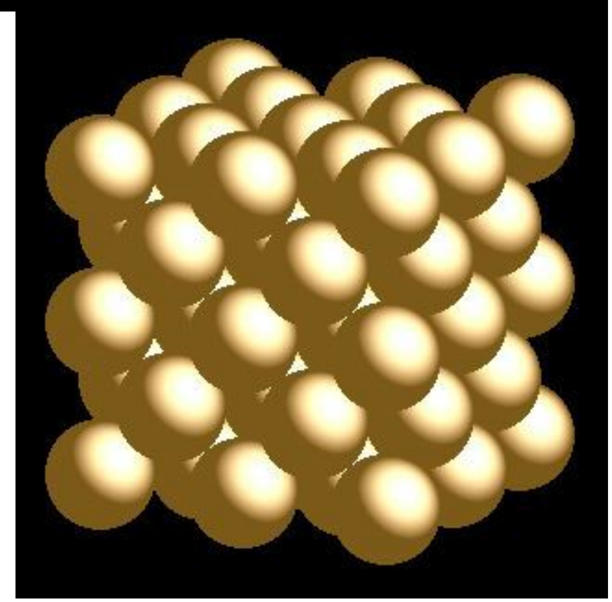
Status: Idle CPS: 22096 DT: 6.7 Lsec: 15.0 52 Cnts 2.275 keV Det: Apollo XLT2 Windowless



Status: Idle CPS: 22096 DT: 6.7 Lsec: 15.0 52 Cnts 2.275 keV Det: Apollo XLT2 Windowless

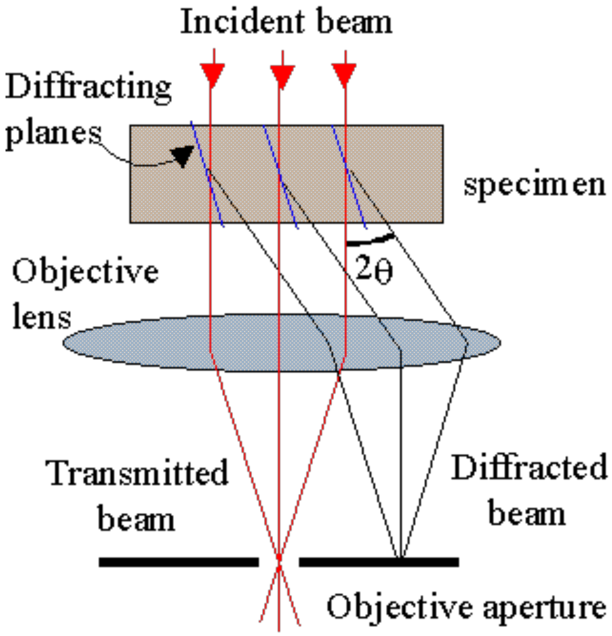


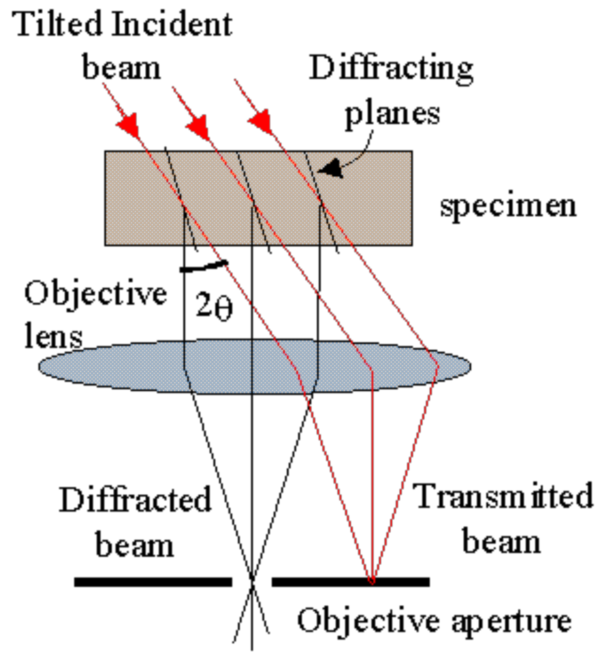




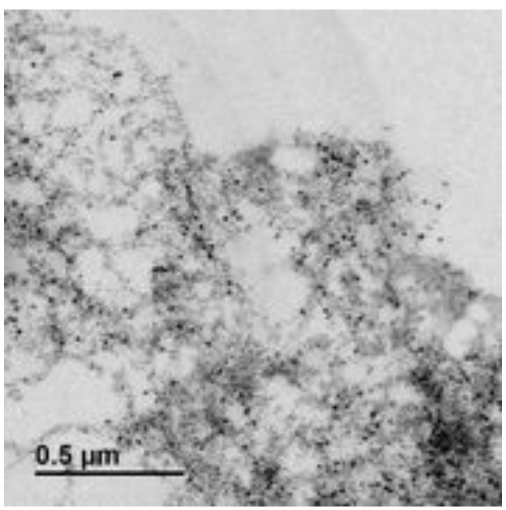
lattice distance is about 2.38A, very close to
the gold (111) plane’s distance 2.36A

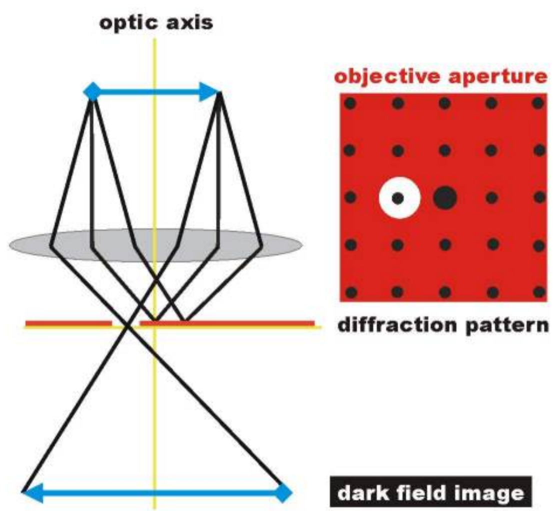
Dark Field





Bright Field Imaging





On-axis Dark Field